Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,319	CONRAD ET AL.	
Examiner	Art Unit	
Charles R. Kasenge	2125	

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Class	Subclass	Date	Examiner
700	95	11/24/2004	ск
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EAST Search; search terms: semiconductor, tool, sampling, metrology	11/24/2004	ск			
					